


<b>Search Notes</b>  	<b>Application/Control No.</b>  10562547	<b>Applicant(s)/Patent Under Reexamination</b>  DUFF ET AL.
	<b>Examiner</b>  CEDRIC CHAN	<b>Art Unit</b>  1797

SEARCHED			
Class	Subclass	Date	Examiner
422	100,62	4/23/2010	CC
436	55,180	4/23/2010	CC
222	52	4/23/2010	CC
73	1.36,1.74	4/23/2010	CC
700	28,32,37,89	4/23/2010	CC

SEARCH NOTES		
Search Notes	Date	Examiner
inventor search (PALM/EAST)	3/25/2010	CC
assignee search (see EAST Search History)	3/25/2010	CC
PCT Search Report of related International Application	3/25/2010	CC
keyword search US/FOR Databases (EAST/EPO,JPO,DERWENT,USPAT,OCR,PGPUB)	4/23/2010	CC
classification search with limiting text	4/23/2010	CC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/C. C./ Examiner.Art Unit 1797	
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